

**Search Notes**

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10/705,764

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

CLARK ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	10/23/2006	CH
455	403	10/23/2006	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	10/23/2006	CH
Combined Text Search	10/23/2006	CH